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AMENDMENTS TO THE CLAIMS WITH MARKINGS TO SHOW CHANGES
MADE, AND LISTING OF ALL CLAIMS WITH PROPER IDENTIFIERS

1. (Currently amended) A device for determining the position of a tool and/or a

load-bearing machine component of a machine tool or production machine,

comprising:

a primary crossbeam disposed between and attached to two movable

support elements and supporting the tool or the machine component,

a rigid secondary crossbeam supported by between the two support

elements; and

a contactless measuring unit connected with the primary crossbeam and

constructed to measure a deflection of the primary crossbeam relative to the

secondary crossbeam.

2. (Original) The device of claim 1, wherein the deflection is dependent on at

least one of an acceleration force, a weight and a processing force exerted

on the tool or the machine component.

3. (Original) The device of claim 1, wherein the secondary crossbeam has a

stiffness perpendicular to a travel direction of the tool or the machine

component that is greater than a stiffness of the primary crossbeam.

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4. (Original) The device of claim 1, wherein the secondary crossbeam is made

of a carbon composite.

5. (Original) The device of claim 1, wherein the measuring unit is arranged in

close proximity to the tool or the machine component.

6. (Original) The device of claim 1, wherein the measuring unit is constructed

as a measuring instrument using laser triangulation.

7. (Original) The device 1, wherein the measuring unit emits a laser beam for

measuring a distance between the primary and secondary crossbeams.

8. (Original) The device of claim 1, wherein the secondary crossbeam

includes a metallic surface, with the measuring unit being constructed for

inductive or capacitive measurement.

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